

Form PTO-1449
(Rev. 8-83)

U.S. Department of Commerce
Patent and Trademark Office

Atty Docket 0756-2414

Serial No.

INFORMATION DISCLOSURE STATEMENT

Applicants: Shunpei YAMAZAKI et al.

Filing Date: December 28, 2001

Group Art Unit

Unassigned

US PTO
10/028276
12/28/01

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
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DB	4,394,688	07/19/1983	Iida.H	348	28	
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						Yes	No
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DB	07-135318	05/23/1995	JP	—	—	Eng Abst	
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DB	10-132749	05/22/1998	JP	—	—		X

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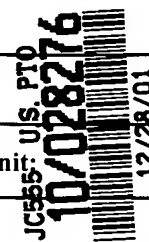
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2633



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Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
OP	10-161363	06/19/1998	JP	—	—	Eng Abst	
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OP	10-294280	11/04/1998	JP	—	—	Eng Abst	
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OP	US Patent Application No.: 09/138,691
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OP	Shimokawa et al., "Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement", pp. 571-578, May 1, 1988, Japanese Journal of Applied Physics, Vol. 27, No. 5

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		Applicants: Shunpei YAMAZAKI et al.	
		Filing Date: December 28, 2001	Group Art Unit: 2673

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OTHER DOCUMENT

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JP

Shimokawa et al., "Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement", pp. 751-758, May 1, 1988, Japanese Journal of Applied Physics, Vol. 27, No. 5

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